

February 2006

FDS8884

N-Channel PowerTrench® MOSFET

30V, **8.5A**, **23m**Ω

General Descriptions

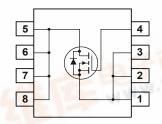
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{DS(on)}$ and fast switching speed.



Features

- Max $r_{DS(on)} = 23m\Omega$ at $V_{GS} = 10V$, $I_D = 8.5A$
- Max $r_{DS(on)} = 30m\Omega$ at $V_{GS} = 4.5V$, $I_D = 7.5A$
- Low gate charge
- 100% R_G Tested
- RoHS Compliant





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		30	V
V _{GS}	Gate to Source Voltage		±20	V
	Drain Current Continuous	(Note 1a)	8.5	Α
ID	Pulsed		40	Α
E _{AS}	Single Pulse Avalanche Energy	(Note 2)	32	mJ
Б	Power dissipation		2.5	W
P_D	Derate above 25°C		20	mW/°C
T _J , T _{STG}	Operating and Storage Temperature		-55 to 150	°C

Thermal Characteristics

	The state of the s			
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Case	(Note 1)	25	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS8884	FDS8884	SO-8	330mm	12mm	2500 units

Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
ΔBV _{DSS} Δ T _J	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu A$, referenced to $25^{\circ}C$		23		mV/°C
1	Zero Gate Voltage Drain Current	V _{DS} = 24V			1	μА
IDSS	Zero date Voltage Brain Guirent	$V_{GS} = 0V$ $T_J = 125^{\circ}C$			250	μΛ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$			±100	nA

On Characteristics (Note 3)

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	1.7	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25°C		-4.9		mV/°C
		$V_{GS} = 10V, I_D = 8.5A,$		19	23	
rpo()	Drain to Source On Resistance	$V_{GS} = 4.5V$, $I_D = 7.5A$,		23	30	mΩ
r _{DS(on)}	Brain to Godice Chinesistance	$V_{GS} = 10V, I_D = 8.5A,$ $T_J = 125^{\circ}C$		26	32	11132

Dynamic Characteristics

C _{iss}	Input Capacitance	V 45V V 6V	475	635	pF
C _{oss}	Output Capacitance	V _{DS} = 15V, V _{GS} = 0V, f = 1MHz	100	135	pF
C _{rss}	Reverse Transfer Capacitance	1 – 1101112	65	100	pF
R_G	Gate Resistance	f = 1MHz	0.9	1.6	Ω

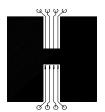
Switching Characteristics (Note 3)

t _{d(on)}	Turn-On Delay Time	.,	5	10	ns
t _r	Rise Time	$V_{DD} = 15V, I_{D} = 8.5A$ $V_{GS} = 10V, R_{GS} = 33\Omega$	9	18	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = 10V, H _{GS} = 3312	42	68	ns
t _f	Fall Time		21	34	ns
Qg	Total Gate Charge	$V_{DS} = 15V, V_{GS} = 10V$ $I_{D} = 8.5A$	9.2	13	nC
Q_g	Total Gate Charge	$V_{DS} = 15V, V_{GS} = 5V$	5.0	7	nC
Q_{gs}	Gate to Source Gate Charge	I _D = 8.5A	1.5		nC
Q_{gd}	Gate to Drain Charge		2.0		nC

Drain-Source Diode Characteristics

V _{SD} Source to Drain Diode Voltage		$I_{SD} = 8.5A$	0.9	1.25	V
V_{SD}	Source to Drain Diode Voltage	I _{SD} = 2.1A	0.8	1.0	V
t _{rr}	Reverse Recovery Time	I _F = 8.5A, di/dt = 100A/μs		33	ns
Q_{rr}	Reverse Recovery Charge			20	nC

1: R_{B,IA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{B,C} is guaranteed by design while R_{B,CA} is determined by the user's board design.



a) 50°C/W when mounted on a 1 in2 pad of 2 oz copper



b) 105°C/W when mounted on a .04 in² pad of 2 oz copper



c) 125°C/W when mounted on a minimun pad

Scale 1: 1 on letter size paper

- 2: Starting $T_J=25^{\circ}C$, L = 1mH, $I_{AS}=8A$, $V_{DD}=27V$, $V_{GS}=10V$. 3: Pulse Test:Pulse Width <300 μ S, Duty Cycle <2%.



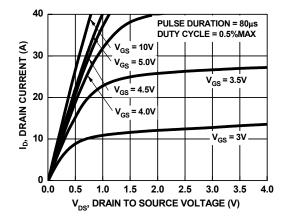


Figure 1. On Region Characteristics

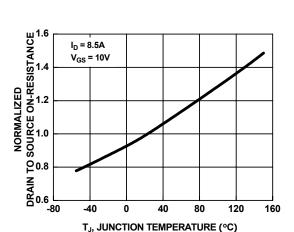


Figure 3. Normalized On Resistance vs Junction Temperature

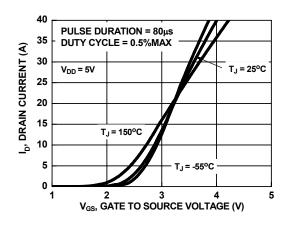


Figure 5. Transfer Characteristics

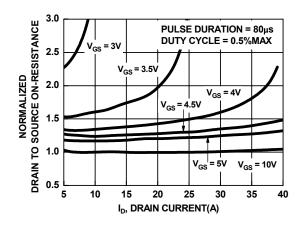


Figure 2. Normalized On-Resistance vs Drain current and Gate Voltage

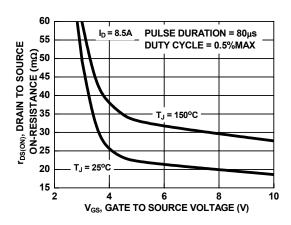


Figure 4. On-Resistance vs Gate to Source Voltage

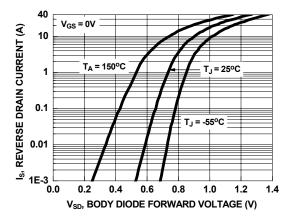
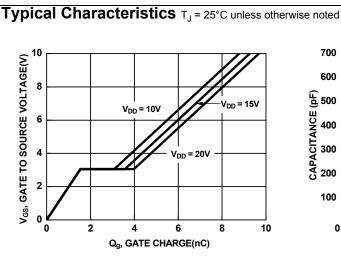


Figure 6. Source to Drain Diode Forward Voltage vs Source Current



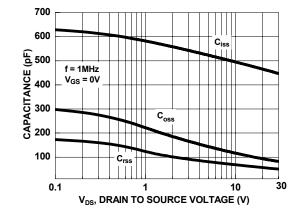
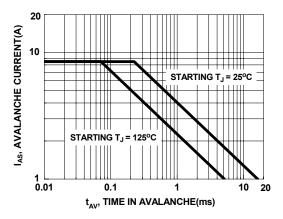


Figure 7. Gate Charge Characteristics

Figure 8. Capacitance vs Drain to Source Voltage



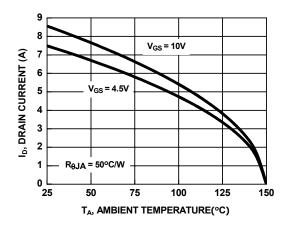
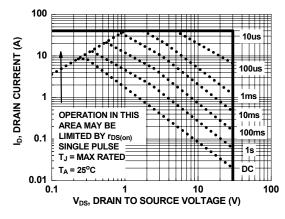


Figure 9. Unclamped Inductive Switching Capability

Figure 10. Maximum Continuous Drain Current vs
Ambient Temperature



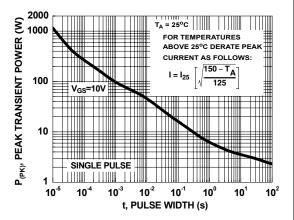


Figure 11. Forward Bias Safe Operating Area

Figure 12. Single Pulse Maximum Power Dissipation

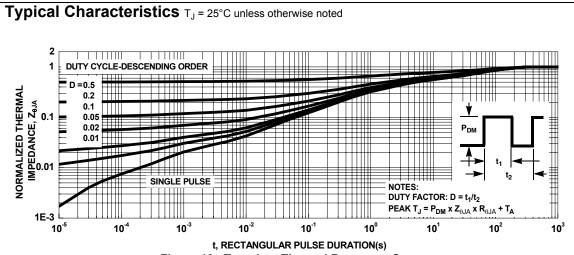


Figure 13. Transient Thermal Response Curve

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